

QUALIFICATION REPORT SUMMARY				
PACKAGE	TEST	CONDITIONS	SAMPLE SIZE	RESULTS
5-SOT_23	Highly Accelerated Stress Test (HAST) ^{1,2}	JEDEC <i>JESD22-A110</i>	3 x 77	Pass
5-SOT_23	Temperature Cycle (TC) ^{1,2}	JEDEC <i>JESD22-A104</i>	3 x 77	Pass
5-SOT_23	Autoclave (AC) ^{1,2}	JEDEC <i>JESD22-A102</i>	3 x 77	Pass
5-SOT_23	High Temperature Storage Life (HTSL) ²	JEDEC <i>JESD22-A103</i>	1 x 77	Pass
5-SOT_23	Solder Heat Resistance (SHR) ¹	<i>ADI-0049</i>	3 x 11	Pass
5-SC70	Solder Heat Resistance (SHR) ¹	<i>ADI-0049</i>	1 x 30	Pass
8-SOIC_N	Solder Heat Resistance (SHR) ¹	<i>ADI-0049</i>	1 x 30	Pass
8-SOIC_N	Latch-Up	JEDEC <i>JESD78</i>	1 x 9	Pass
8-SOIC_N	Electrostatic Discharge <i>Human Body Model</i>	ANSI/ANSI/ESDA/JEDEC <i>JS-001-2010</i>	1 x 24	Pass 4kV
5-SOT_23	Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	1 x 15	Pass 1.5kV
5-SC70	Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	1 x 15	Pass 1.5kV
8-SOIC_N	Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	1 x 15	Pass 1.5kV

¹ Preconditioned per JEDEC/IPC J-STD-020

² Test is not a Gating item for Reliability Qualification